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Integration of a GaAs solar cell in a hybrid photovoltaic-thermoelectric system

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Context

Photovoltaic cell (PV) converts only partially energy above the bandgap into electricity.

The rest is either not absorbed or converted into heat.

Infrared part of the spectrum is not absorbed.



Objectives

Create a PV cell optimised for integration in hybrid PV-TEG system

- Use of a thermally conductive substrate
- Reduce thermal resistivity at the PV-TEG interface

Excess heat loss is converted with the thermoelectric generator (TEG) via Seebeck effect [1].

schematic representation of a hybrid PV-TEG system

ARC

deposition

(optional)



Process for design and transfer of a PV cell onto a host substrate



Resist

Wafer etching)

removal

Back contact deposition

- Metal deposition via sputtering
- Electric back contact PV cell Growth wafer
- Contact resistivity checked via transfert length method (TLM)

Pad lithography for TLM structures : ECI 5µm

Pad structure after Ti-Au deposition via sputtering



Finger

deposition

Finger

Lithography





ARC



TLM measurement on probbing bench

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